DATA SHEET

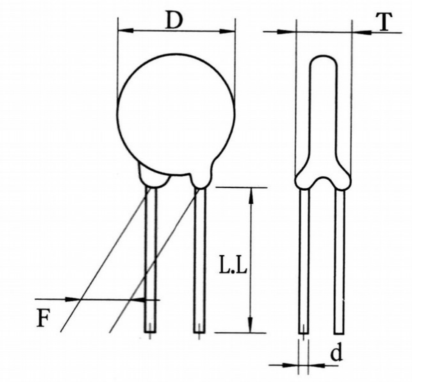
Date: 12-Oct-2017

customer name	TME	Description	10KV-E-222M	Quantity	PCS
customer lot no.		Material lot no.		Temperature	25℃
Project Lot no.		Sampling Standard	MIL-STD-105E, normal inspection, inspection level Ⅱ		
Allow acceptable quality level	Critical Defect: AC=0, RE=1; Major Defect: AQL=0.4; Minor Defect: AQL=0.65				

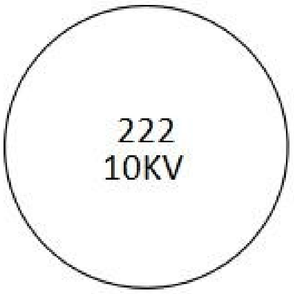
Sampling Qty	PCS	Acceptable Qty	Minor Defect	Major Defect	Critical Defect	Disqualified Qty	Minor Defect	Major Defect	Critical Defect
			0 PCS	0 PCS	0 PCS		1 PCS	1 PCS	1 PCS

Project	Capacitance (C)		Dissipation Factor (D.F)	Insulation Resistance (I.R)	Voltage Proof (T.V)	Pitch (P)	diameter of leader wire (d)	diameter for the chip (D)	Thickness (T)	length of the lead wire (L.L)	Sol	Appearance
Standard Value NO.	PF	1760	1.00	10GΩ	12KV	10.0	0.57mm	11.0	4.4	20.0		
		2640	Maximum	Minimum	DC	±1.5mm	±10%	Maximum	Maximum	Minimum		

Product Shape:



logo printing:



Remark	1.ref. to the Capacitance (c), Dissipation Factor (D.F), Instrumentation:TH2617A,1KHZ(Rate),1.0V(2.Instrumentation for Insulation Rediddtance:TH2683 3.Instrumentation for Voltage Proof: LK2674A Voltage Testing) 4.Dimensional inspection measuring tool for Appearance: Vernier caliper (0.02mm)

Adjudged	*Qualified Disqualified	Inspector	Li Shuipeng	Supervisor	Zheng Xiuwen